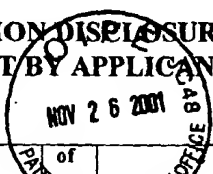
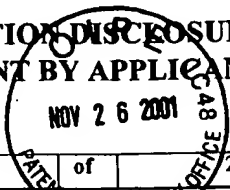


FORM PTO-1449/A and B (Modified)		APPLICATION NO.: 09/836,743	ATTY. DOCKET NO.: V0077/7192
INFORMATION DISCLOSURE STATEMENT BY APPLICANT 		FILING DATE: April 17, 2001	
		APPLICANT: Liebert et al.	
		GROUP ART UNIT: Not Yet Assigned 2881	EXAMINER: Not Yet Assigned K. NGUYEN
Sheet 1 of			

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Sheet	2	of	2

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Examiner's Initials#	Cite No.	Include name of the author (in CAPITAL LETTERS) title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, relevant page(s), volume-issue number(s), publisher, city and/or country where published.	Translation (Y/N)
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#EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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